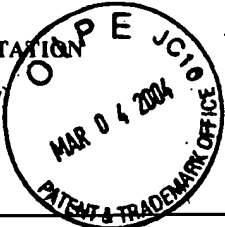


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				APPLICANT Cardinal Glass Industries, Inc.			
				FILING 12/31/03		GROUP Unknown	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	X	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
ku	X	3,904,506	09/09/75	Carmichael, et al.	204	298	X
↓	X	3,968,018	07/06/76	Lane, et al.	204	192	X
↓	X	4,214,972	07/29/80	Shintock	204	298	X
↓	X	5,054,421	10/08/91	Ito, et al.	118	723	X
↓	X	5,273,634	12/28/93	Fukui, et al.	204	192.34	X
↓	X	5,424,130	06/13/95	Nakanishi, et al.	428	410	X
↓	X	5,616,532	04/01/97	Heller, et al.	502	242	X
↓	X	5,853,866	12/29/98	Watanabe, et al.	428	312.8	X
↓	X	5,874,701	02/23/99	Watanabe, et al.	204	157.15	X
↓	X	5,939,194	08/17/99	Hashimoto, et al.	428	411.1	X
↓	X	5,969,470	10/19/99	Druz, et al.	313	359.1	X
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
ku	X	WO 02/05708 A2	01/24/02	PCT	A61B	5/00	X
↓	X	WO 00/37377	06/29/00	PCT	CO3C	17/34	X
↓	X	WO 00/37376	06/29/00	PCT	CO3 C	17/34	X
X	X	X	X	X	X	X	X
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
ku	X	Keem, Dr. John "Deposition and Surface Modification With Anode Layer Ion Sources" <u>Veeco Instruments and Society of Vacuum Cleaners</u> (PSE Presentation, (September 11, 2002)					
ku	X	Blacker, Richard, et al. "Ion Beam Precleaning of Glass with ALS" <u>Veeco Instruments 4th International Conference of Coatings on Glass Presentation</u> (November 2002)					
X	X	X	X	X	X	X	X
EXAMINER		KAPLA MOORE		DATE CONSIDERED 7 DEC 2005			
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	5,982,101	11/09/99	Fremgen, Jr. et al.	315	111.91		
	6,090,489	07/18/00	Hayakawa, et al.	428	409		
	6,139,803	10/31/00	Watanabe, et al.	422	121		
	6,150,755	11/21/00	Druz, et al.	313	359.1		
	6,165,256	12/26/00	Hayakawa, et al.	106	13		
	6,191,062	02/20/01	Hayakawa, et al.	502	159		
	6,210,779	04/03/01	Watanabe, et al.	428	208		
	6,224,718	05/01/01	Meyer	204	192.12		
	6,225,747	05/01/01	Fremgen, Jr. et al.	315	111.91		
	6,368,664	04/09/02	Veerasamy, et al.	427	249.7		
	6,652,974	11/25/03	Krisko	428	428		
✓	6,660,365	12/09/03	Krisko, et al.	428	149		
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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
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